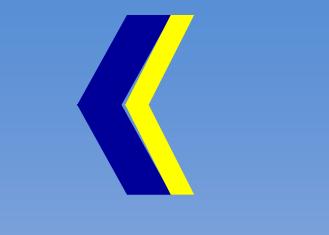


Field-Programmable Logic and its Applications

Oslo, Norway, Aug. 29-31, 2012

Fault Detection and Avoidance of FPGA

in Various Granularities



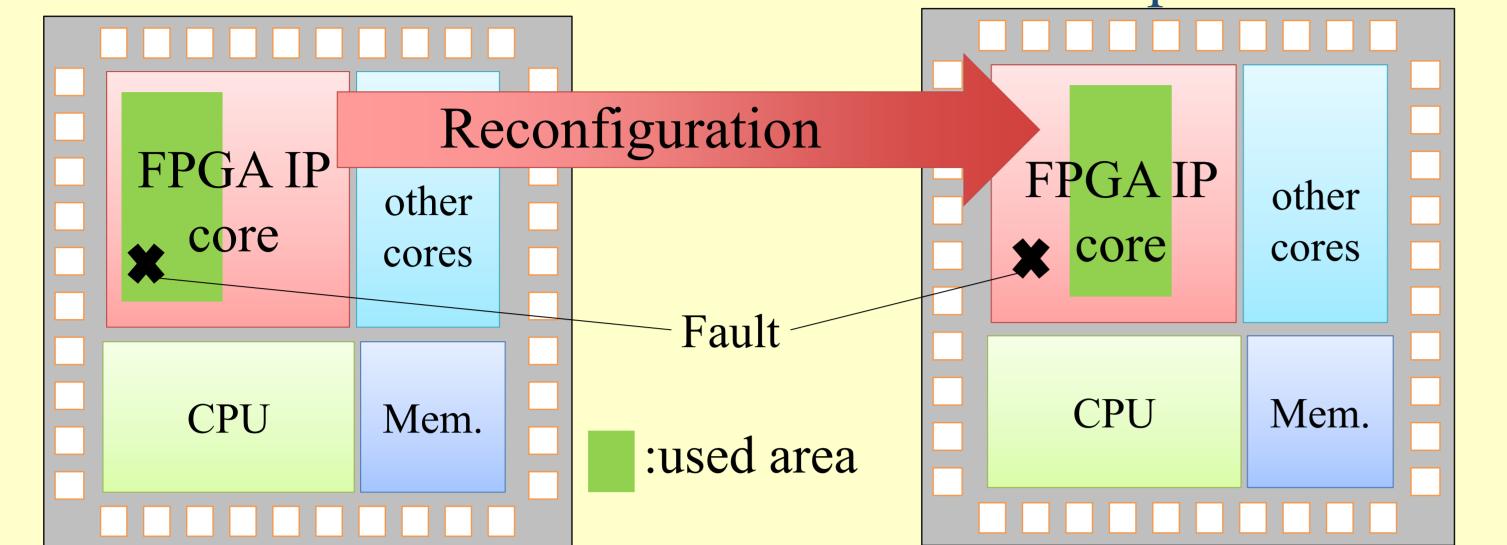
Kumamoto University

Kazuki Inoue, Yuki Nishitani, Motoki Amagasaki, Masahiro Iida, Morihiro Kuga, Toshinori Sueyoshi Kumamoto University, Japan

1. Introduction

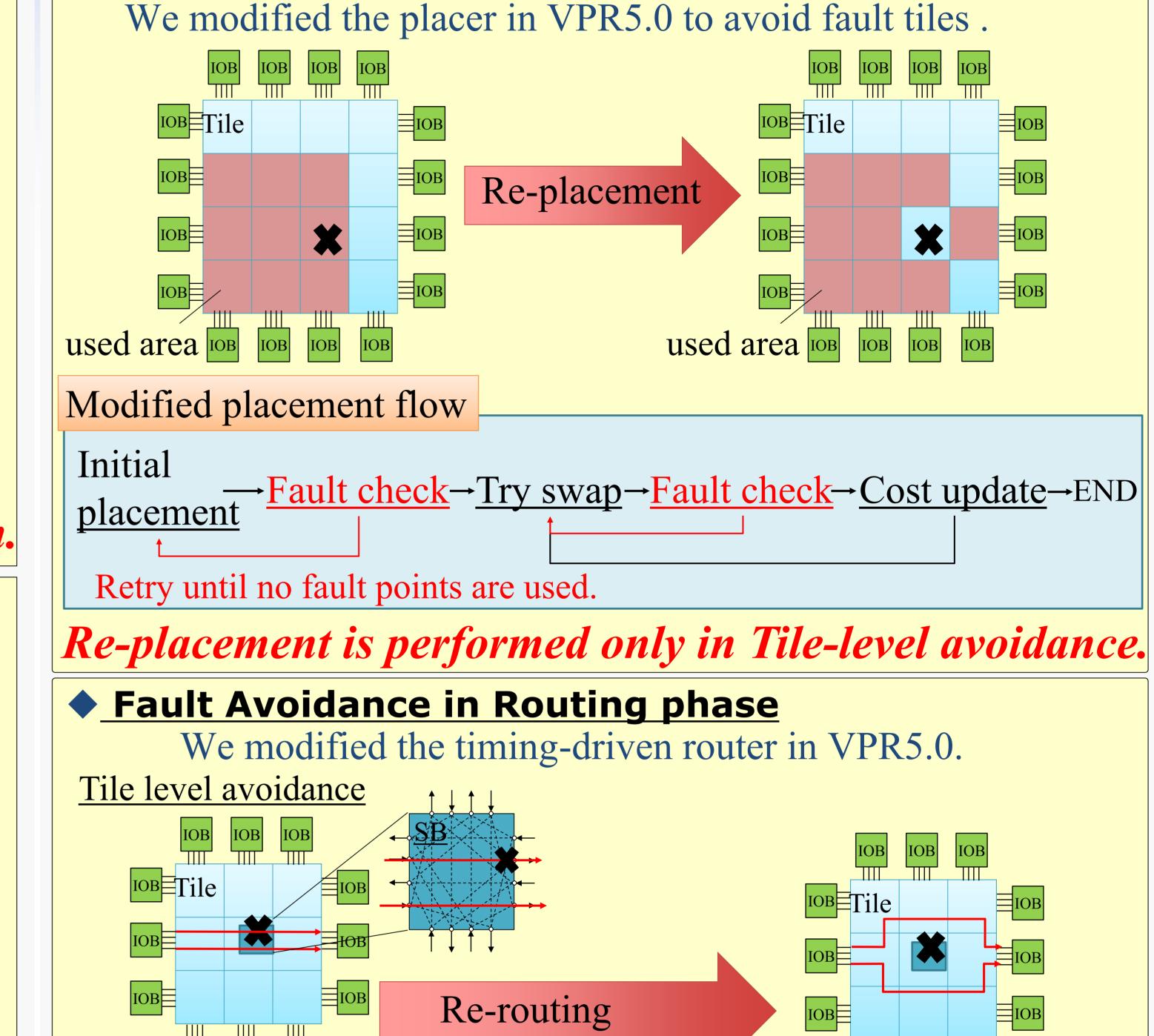
Fault Tolerant Technique with Reconfiguration

A Fault Tolerance is crucial for SoCs in dependable systems. We focus on the FPGA IP core to realize dependable SoCs.



<u>3. Fault Avoidance with CAD tools</u>

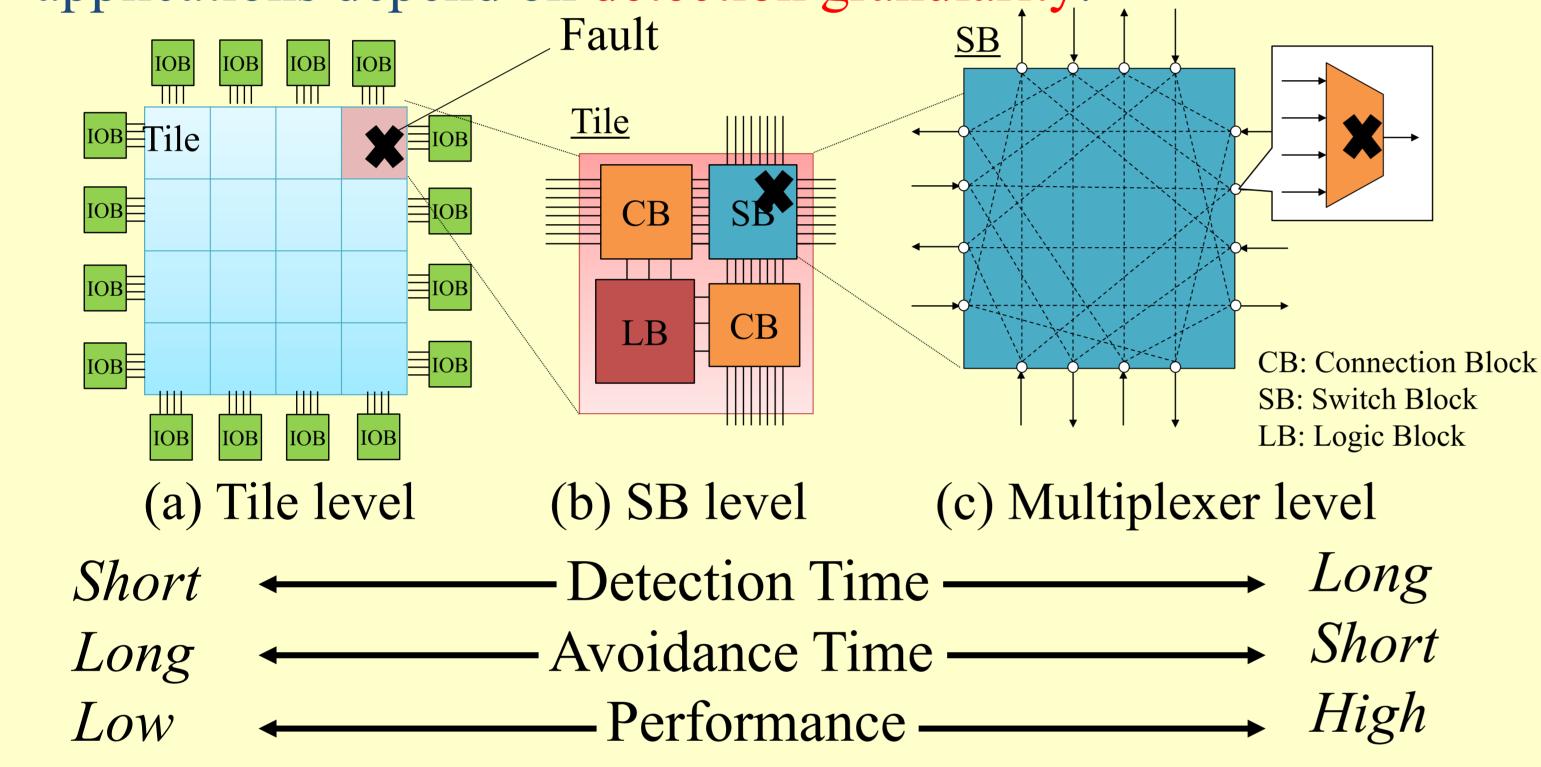
Fault Avoidance in Placement phase



FPGA can easily recover from faults using reconfiguration.

Key points of Fault Tolerant technique

Recovery (detection and avoidance) time and performance of applications depend on detection granularity.



All signals cannot go through the fault Tile.

Multiplexer level avoidance

We propose fault detection and avoidance technique

for global interconnects in various granularities.

2. Fault Detection Technique

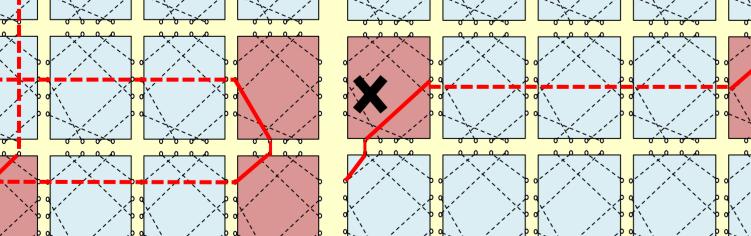
Key Idea of fault-detection

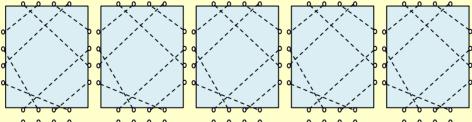
We combine several test paths to identify the fault points correctly.

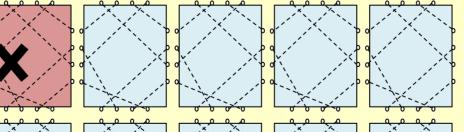


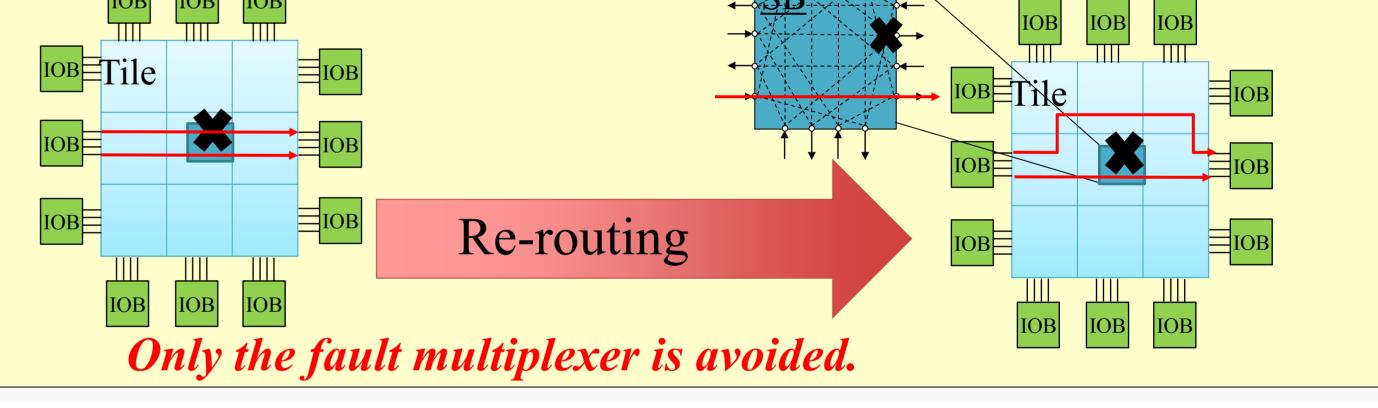
SB(Switch Block) test signal

It's difficult to identify the fault point with one path.









4.Evaluation

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Evaluation Conditions Target Device		Target Fault					
em	value	Stuck-at single fault at the SB					
rray size	16×16	Detection Method					
ogic block	4×6-LUT	Method(1): Test paths (a) and (b)					
nannel width	48	Method(2): Test paths (b), (c), and (d)					
of I/O pins	128						
onfiguration bits	136,896	Avoidance Method					
designed by 65 nm process technology		Tile-level: Re-placement and re-routing					
		Multiplexer (MUX) -level: Re-routing only					

Evaluation Results Results of fault detection

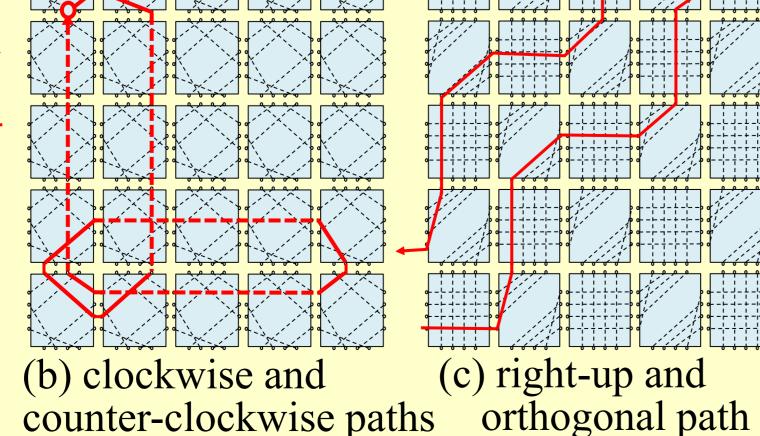
Test path type-A

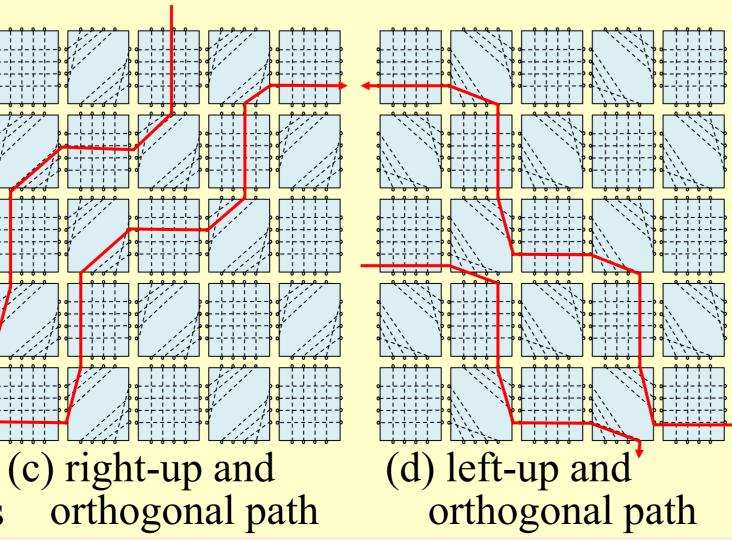
Test path type-B

De-B Combination of paths A and B.

Proposed test paths

(a) orthogonal path





Test paths (a) and (b) were proposed in previous work. They achieved 100% fault coverage for interconnect testing.
(c) and (d) are newly prepared for fault diagnosis in this work.

Ι	Detection method				Method	(1)	Meth	od (2)				
d	letection time	ection time (clock cycle)				992	1,122,970					
#	of fault tiles	of fault tiles (worst/best)				4/4	7/1					
#	t of fault mult	fault multiplexers (worst/best)				/12		14/1				
The pa	The paths of Method (2) detected the fault SB correctly											
<i>with 40% additional time compared to Method(1)!!</i> <u>Circuit delays affected by fault-avoidance[ns]</u> <u>Avoidance time[s]</u>												
	No fault	Met	thod (1) Mo		hod (2)	Cir	cuit	Tile	MUX			
avoid . lev	vel	Tile	MUX	Tile	MUX	C62	288	4.25	0.94			
C6288	96.7	N/A	96.6	100.3	96.2	core	dic	3.60	0.87			
cordic	103.4	N/A	102.2	111.4	93.9	ex4	p	3.28	0.38			
ex4p	46.4	N/A	46.7	49.1	47.4	N/A: Implementation failed.						
	# of fault-candidates Method (1) : 25 Tiles, 48 MUXs, Method (2): 2 Tiles, 2 MUXs. MUX-level avoidance achieved high success ratio of implementation											

and performance same as no fault FPGA in short avoidance time!!